

**Notice of References Cited**

Application/Control No.

10/825,357

Applicant(s)/Patent Under  
Reexamination  
LEE ET AL.

Examiner

VINH T. LAM

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0000576 A1	01-2002	Inukai, Kazutaka	257/202
*	B	US-6,690,034 B2	02-2004	Fujimoto et al.	257/72
*	C	US-6,909,409 B2	06-2005	Tanada, Yoshifumi	345/51
*	D	US-6,924,602 B2	08-2005	Komiya, Naoaki	315/169.3
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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